

Title (en)

Semiconductor device and method of screening the same.

Title (de)

Halbleiteranordnung und ihre Prüfungsverfahren.

Title (fr)

Dispositif à semi-conducteurs et méthode pour l'examiner.

Publication

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Application

**EP 91107613 A 19910510**

Priority

JP 11994890 A 19900511

Abstract (en)

A semiconductor device comprising a plurality of circuit blocks (12, 13, 102, 103) to which various potentials, including at least one potential either raised or lowered, are assigned. The device further comprises means (11, 101) for selectively and reversely changing the potentials assigned to the circuit blocks. <IMAGE> <IMAGE>

IPC 1-7

**G11C 5/14; G11C 29/00**

IPC 8 full level

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CPC (source: EP KR US)

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